

## 12500 TI Boulevard, MS 8640, Dallas, Texas 75243

# PCN#20180828000.1 Qualification of TI Clark as an additional Assembly & Test site for select devices Change Notification / Sample Request

**Date:** August 28, 2018 **To:** MOUSER PCN

#### Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The proposed first ship date is indicated on page 3 of this notification, unless customer agreement has been reached on an earlier implementation of the change.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN www admin team@list.ti.com).

Sincerely,

PCN Team SC Business Services

## 20180828000 Attachment: 1

## **Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

**DEVICE**CSD95480RWJT
CSD95481RWJT
CSD95482RWJT

**CUSTOMER PART NUMBER** 

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Technical details of this Product Change follow on the next page(s).

	<b>CN Number:</b> 20180828000.1 <b>PCN Date:</b> Aug. 28, 2018				
Title: Qualification of TI Clark as an additional Assembly & Test site for select devices					
Customer Contact: PCN Manager Dept: Quality Services					
Proposed 1st Chin Date: Nov. 39, 2019 Estimated Sample Date pr	ovided at				
Proposed 1 <sup>st</sup> Ship Date: Nov 28, 2018  Availability: sample requirements of the provided sample requirements of the provided sample.					
Change Type:					
Assembly Site Design Wafer Bump S	Site				
	er Bump Material				
	Wafer Bump Process				
Mechanical Specification					
	Wafer Fab Materials				
	ocess				
PCN Details					
Description of Change:					
Texas Instruments is pleased to announce the qualification of TI Clark as an addition	nal Assembly				
& Test site for select devices. Assembly differences are as follows:					
Assembly Site	nbly City				
UTAC Thai Limited NSE THA Bar	Bangkok				
TI Clark QAB PHL Ange	les City				
Material differences:					
UTAC Thai Limited TI Clark					
Controller mount compound PZ0138 4206201					
Mold Compound         CZ0351         4222198					
Lead frame finish Matte Sn (Roughened) NiPdAu (Roughened)					
Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.					
Reason for Change:					
Continuity of Supply					
Continuity of Supply					
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / r	negative):				
	negative):				
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / r	negative):				
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / r	re driven g the evised ite. There is				

#### Sample Product Shipping Label (not actual product label) Assembly Site UTAC Thai Limited Assembly Site Origin (22L) ASO: NSE TI Clark Assembly Site Origin (22L) ASO: QAB TEXAS INSTRUMENTS (1P) SN74LS07NSR MADE IN: Malaysia 2DC: 2Q; (a) 2000 (D) 0336 (31T)LOT: 3959047MLA MSL 2 /260C/1 YEAR SEAL DT 4W) TKY(1T) 7523483\$12 MSL 1 /235C/UNLIM 03/29/04 OPT: ITEM: (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MVC (L)T0:1750 5A LBL: (23L) ACO: MYS **Product Affected:** CSD59945RWJ CSD59956RWJ CSD95480RWJT SN1703022RWJ CSD59950RWJ CSD59985RWJ CSD95481RWJ SN1803048RWJ CSD59951RWJ CSD59986RWJ CSD95481RWJT CSD59952RWJ CSD59995ARWJ CSD95482RWJ

# **Qualification Report**CSD95480RWJ Power Stage Product Qualification

CSD95482RWJT

CSD95480RWJ

Approve Date 28-August-2018

#### **Product Attributes**

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Attributes	Qual Device: CSD95480RWJ	Qual Device: CSD95480RWJ	Qual Device: CSD95480RWJ	Qual Device: CSD95480RWJ	
Assembly Site	CLARK	UTAC	UTAC	PSI	
Package Family	QFN/SON	ON QFN/SON QFN/		ON QFN/SON	
Flammability Rating	ammability Rating UL 94 V-0 UL 94 V-0		UL 94 V-0 UL 94 V-0		
Wafer Fab Supplier	MIHO CFAB CFAB	MIHO CFAB CFAB	FFAB AIZU AIZU	MIHO CFAB CFAB	
Wafer Process  LV2010  NEXFET GEN2.  LV2010  NEXFET GEN2.  LV2010		LBC7 NEXFET GEN2.2 LV2010 NEXFET GEN2.2 LV2010	LBC7 NEXFET GEN2.2 LV2010 NEXFET GEN2.2 LV2010	LBC7 NEXFET GEN2.2 LV2010 NEXFET GEN2.2 LV2010	

- QBS: Qual By Similarity

CSD59955RWJ

- Qual Device CSD95480RWJ is qualified at LEVEL2-260C
- Device CSD95480RWJ contains multiple dies

#### **Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: CSD95480RWJ	Qual Device: CSD95480RWJ	Qual Device: CSD95480RWJ	Qual Device: CSD95480RWJ
AC	Autoclave 121C	96 Hours	-	3/231/0	-	3/231/0
DIOL	Dynamic Intermittent Operating Life (4 min cycles)	10000 Cycles	3/231/0	3/231/0	-	-
ED	Electrical Characterization	Per Datasheet Parameters	Pass	-	-	-
HAST	Biased HAST, 110C/85%RH	264 Hours	3/231/0	-	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	3/231/0	3/231/0
HBM	ESD - HBM	2500 V	-	-	1/3/0	1/3/0
CDM	ESD - CDM	1500 V	-	-	1/3/0	1/3/0
HTOL	Life Test, 125C	1000 Hr	-	3/231/0	3/231/0	-
HTSL	High Temp Storage Bake 150C	1000 Hours	3/231/0	3/231/0	3/231/0	3/231/0
LU	Latch-up	Per JESD74	-	-	1/6/0	1/6/0
TC	Temperature Cycle, - 55/125C	700 Cycles	3/231/0	3/231/0	3/231/0	-
UHAST	Unbiased HAST, 130C/85%RH	96 Hours	3/231/0	-	3/231/0	-

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

THIS INFORMATION RELATING TO QUALITY AND RELIABILITY IS PROVIDED "AS IS." Product information detailed in this report may not accurately reflect TI's current product materials, processes and testing used in the construction of the TI products. Customers are solely responsible to conduct sufficient engineering and additional qualification testing to determine whether a device is suitable for use in their applications. Using TI products outside limits stated in TI's datasheet may void TI's warranty. See TI's Terms of Sale at "http://www.ti.com/lsds/ti/legal/termsofsale.page"

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com